

Amendments To The Claims

Please cancel Claims 28-38 without prejudice. The following list of the claims replaces all prior versions and lists of the claims in this application.

Claims 1-16 (Canceled).

17. (Currently amended) A microelectronic device, comprising:
a substrate having a plurality of doped regions therein;
a patterned feature located over the substrate and ~~over a~~ over the plurality of doped regions, the patterned feature being part of a transistor and comprising at least one electrode, the electrode being situated ~~proximate a~~ proximate the plurality of doped ~~layers~~ regions; and
a sill located within the electrode, the sill comprising at least one impurity and adapted for modifying an electrical property of at least one member adjacent the electrode.

18. (Original) The microelectronic device of claim 17 wherein the sill is formed prior to the patterning of the electrode.

19. (Original) The microelectronic device of claim 17 wherein the sill is formed in the electrode, the electrode and partially etched to reduce the thickness of the electrode and the sill.

20. (Original) The microelectronic device of claim 17 wherein the sill comprises at least two distinct and segregated impurities.

21. (Original) The microelectronic device of claim 17 wherein the substrate comprises diamond.

22. (Original) The microelectronic device of claim 17 wherein the substrate comprises strained silicon.

23. (Original) The microelectronic device of claim 17 wherein the impurity comprises germanium.

24. (Original) The microelectronic device of claim 17 wherein the electrode impurity concentration ranges between about 1×10^{13} atoms/cm² and about 1×10^{19} atoms/cm².

25. (Original) The microelectronic device of claim 17 wherein the sill comprises silicon germanium.

26. (Original) The microelectronic device of claim 17 wherein the sill comprises strained silicon.

27. (Currently amended) The microelectronic device of claim 17 wherein the ~~second~~ sill comprises diamond.

Claims 28-38 (Canceled).